

AMENDMENTS TO THE SPECIFICATION:

Please replace paragraph [0042], with the following rewritten paragraph:

[0042] With reference to Figure 2, a test handling apparatus 100 according to a first embodiment of the present invention comprises a tester interface 110, a first connection, which is a switch 120, links the tester interface 110 and a first device interface in the form of a first test socket 130 and a second connection, which is a switch 120, links the tester interface 110 and a second device interface in the form of a second test socket 230. The interface 110 may comprise a docking plate or receptacle 112, depending on the test set up condition for external communications with a tester 80 by either direct docking or cable connection. The interface 110 is electrically connected to the switch 120 by a connector 122. The switch 120 is a 1x2 change-over switch which is operable to alternate the electrical connection 128 from connectors 122-124 (position A or link to the first connection), to connectors 122-126 (position B or link to the second connection). Connectors 124 and 126 are electrically connected to the first test socket 130 and the second test socket 230 respectively. The test handling apparatus 100 further comprises a loading/unloading assembly 150, which is movable between the input sections 160 and 260 (position P11), the test sockets 130 and 230 (position P12), and the output sections 170 and 270 (position P13).